International

- Advanced Process Technology
- Isolated Package
- High Voltage Isolation = 2.5KVRMS (5)
- Sink to Lead Creepage Dist. = 4.8mm
- Fully Avalanche Rated
- Lead-Free

Description

Fifth Generation HEXFETs from International Rectifier utilize advanced processing techniques to achieve extremely low on-resistance per silicon area. This benefit, combined with the fast switching speed and ruggedized device design that HEXFET Power MOSFETs are well known for, provides the designer with an extremely efficient and reliable device for use in a wide variety of applications.

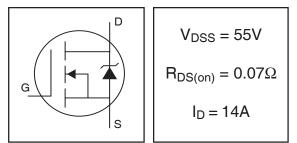
The TO-220 Fullpak eliminates the need for additional insulating hardware in commercial-industrial applications. The moulding compound used provides a high isolation capability and a low thermal resistance between the tab and external heatsink. This isolation is equivalent to using a 100 micron mica barrier with standard TO-220 product. The Fullpak is mounted to a heatsink using a single clip or by a single screw fixing.

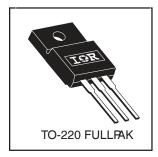
Absolute Maximum Ratings

IRFIZ24NPbF

PD - 94808

HEXFET[®] Power MOSFET





	Parameter	Max.	Units
$I_D @ T_C = 25^{\circ}C$	Continuous Drain Current, V _{GS} @ 10V	14	
I _D @ T _C = 100°C	Continuous Drain Current, V _{GS} @ 10V	10	A
I _{DM}	Pulsed Drain Current 0 6	68	
$P_D @T_C = 25^{\circ}C$	Power Dissipation	29	W
	Linear Derating Factor	0.19	W/°C
V _{GS}	Gate-to-Source Voltage	± 20	V
E _{AS}	Single Pulse Avalanche Energy@6	71	mJ
I _{AR}	Avalanche Current [®]	10	A
E _{AR}	Repetitive Avalanche Energy ^①	2.9	mJ
dv/dt	Peak Diode Recovery dv/dt 36	5.0	V/ns
TJ	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		°C
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)	
	Mounting torque, 6-32 or M3 screw	10 lbf•in (1.1N•m)	

Thermal Resistance

	Parameter	Тур.	Max.	Units	
R _{0JC}	Junction-to-Case		5.2	0000	
R _{0JA}	Junction-to-Ambient		65	°C/W	

Electrical Characteristics @ T_J = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Conditions
V _{(BR)DSS}	Drain-to-Source Breakdown Voltage	55			V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS} / \Delta T_J$	Breakdown Voltage Temp. Coefficient		0.052		V/°C	Reference to 25°C, I _D = 1mA®
R _{DS(on)}	Static Drain-to-Source On-Resistance			0.07	Ω	V _{GS} = 10V, I _D = 7.8A ④
V _{GS(th)}	Gate Threshold Voltage	2.0		4.0	V	$V_{DS} = V_{GS}, I_D = 250 \mu A$
9 _{fs}	Forward Transconductance	4.5			S	$V_{DS} = 25V, I_D = 10A$
1	Drain-to-Source Leakage Current			25	- μΑ	$V_{DS} = 55V, V_{GS} = 0V$
IDSS	Brain to Cource Leakage Current			250		$V_{DS} = 44V, V_{GS} = 0V, T_J = 150^{\circ}C$
1	Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
I _{GSS}	Gate-to-Source Reverse Leakage			-100		V _{GS} = -20V
Qg	Total Gate Charge			20		I _D = 10A
Q _{gs}	Gate-to-Source Charge			5.3	nC	$V_{DS} = 44V$
Q _{gd}	Gate-to-Drain ("Miller") Charge			7.6		V_{GS} = 10V, See Fig. 6 and 13 \circledast
t _{d(on)}	Turn-On Delay Time		4.9			$V_{DD} = 28V$
t _r	Rise Time		34			I _D = 10A
t _{d(off)}	Turn-Off Delay Time		19		ns	$R_G = 24\Omega$
t _f	Fall Time		27			R _D = 2.6Ω, See Fig. 10 ⊕ 6
	laternal Durin laduaterna		4 5			Between lead,
L _D	Internal Drain Inductance		4.5		الم	6mm (0.25in.)
	Internal Source Inductance		7.5			from package
Ls						and center of die contact
C _{iss}	Input Capacitance		370			$V_{GS} = 0V$
C _{oss}	Output Capacitance		140		pF	V _{DS} = 25V
C _{rss}	Reverse Transfer Capacitance		65		1 11	<i>f</i> = 1.0MHz, See Fig. 5⑥
С	Drain to Sink Capacitance		12			f = 1.0MHz

Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
Is	Continuous Source Current			14		MOSFET symbol
	(Body Diode)			14	A	showing the
I _{SM}	Pulsed Source Current			00		integral reverse
	(Body Diode) ① ⑥		- 68	08	p-n junction diode.	
V _{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 7.8A, V_{GS} = 0V \textcircled{4}$
t _{rr}	Reverse Recovery Time		56	83	ns	$T_J = 25^{\circ}C, I_F = 10A$
Q _{rr}	Reverse RecoveryCharge		120	180	μC	di/dt = 100A/µs ④ ⑥
t _{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by $L_{S}+L_{D}$)				

Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See fig. 11)
- O V_{DD} = 25V, starting T_J = 25°C, L = 1.0mH R_G = 25 $\Omega,$ I_{AS} = 10A. (See Figure 12)
- (4) Pulse width \leq 300µs; duty cycle \leq 2%.
- ⑤ t=60s, f=60Hz
- 3 I_{SD} \leq 10A, di/dt \leq 280A/µs, V_{DD} \leq V_{(BR)DSS}, T_J \leq 175°C

© Uses IRFZ24N data and test conditions



International **ISPR** Rectifier

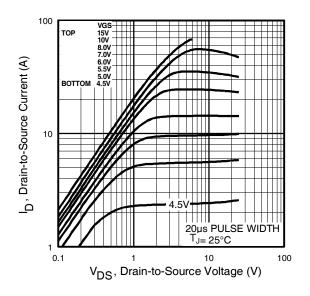


Fig 1. Typical Output Characteristics

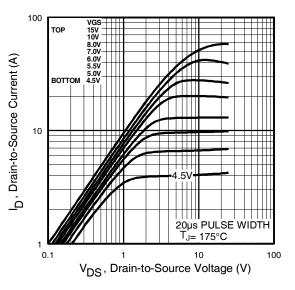


Fig 2. Typical Output Characteristics

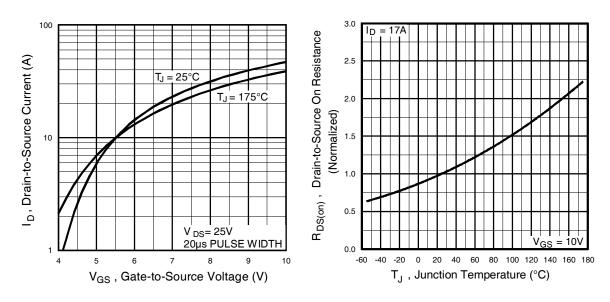


Fig 4. Normalized On-Resistance Vs. Temperature

Fig 3. Typical Transfer Characteristics

International

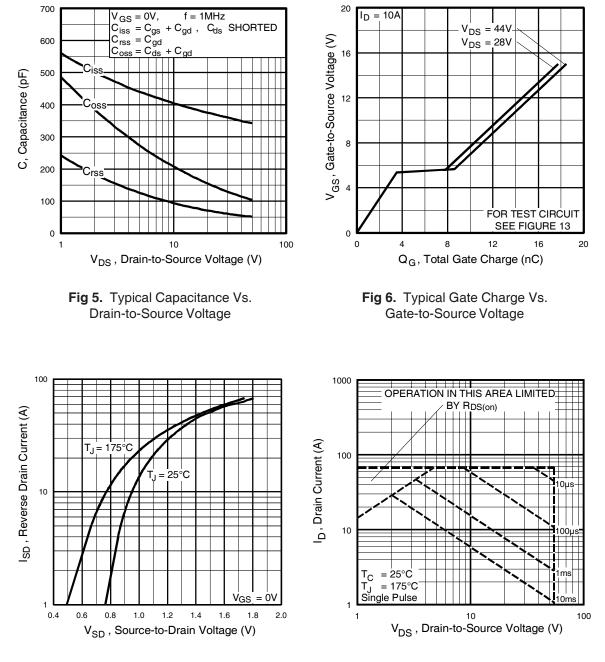
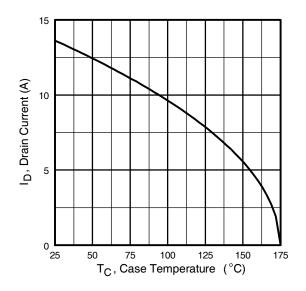
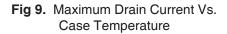


Fig 7. Typical Source-Drain Diode Forward Voltage

Fig 8. Maximum Safe Operating Area

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IRFIZ24NPbF

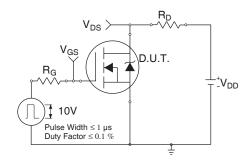


Fig 10a. Switching Time Test Circuit

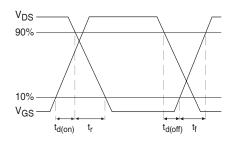


Fig 10b. Switching Time Waveforms

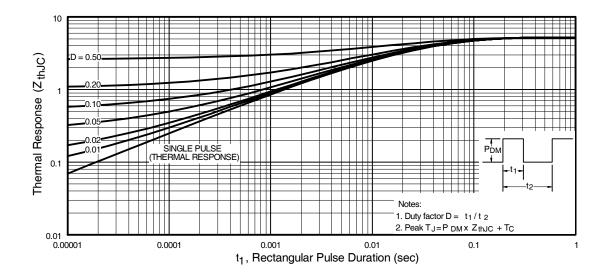


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

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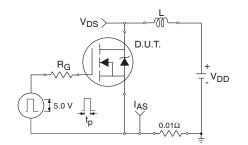


Fig 12a. Unclamped Inductive Test Circuit

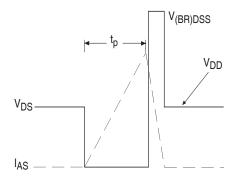


Fig 12b. Unclamped Inductive Waveforms

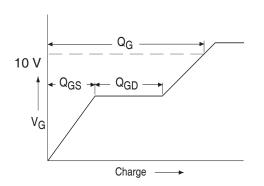
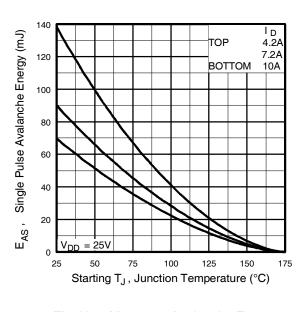
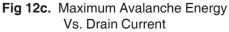


Fig 13a. Basic Gate Charge Waveform





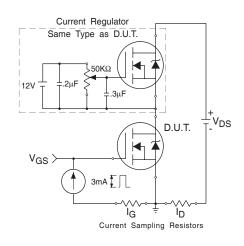
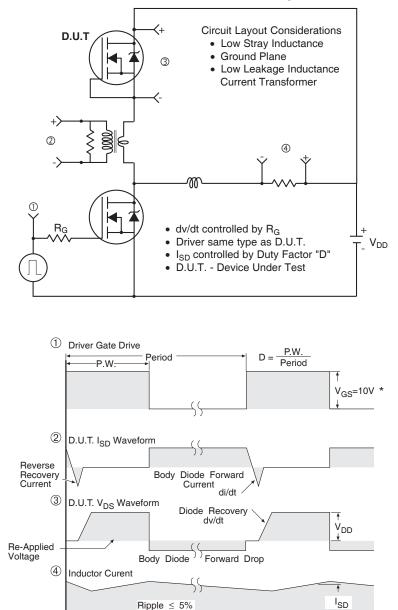


Fig 13b. Gate Charge Test Circuit



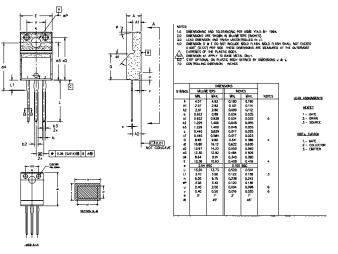
Peak Diode Recovery dv/dt Test Circuit

* $V_{GS} = 5V$ for Logic Level Devices

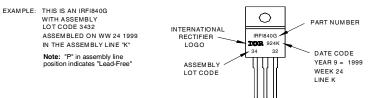
Fig 14. For N-Channel HEXFETS

TO-220 Full-Pak Package Outline

Dimensions are shown in millimeters (inches)



TO-220 Full-Pak Part Marking Information



Data and specifications subject to change without notice.

International

IR WORLD HEADQUARTERS: 233 Kansas St., El Segundo, California 90245, USA Tel: (310) 252-7105 TAC Fax: (310) 252-7903 Visit us at www.irf.com for sales contact information.11/03 Note: For the most current drawings please refer to the IR website at: <u>http://www.irf.com/package/</u>

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